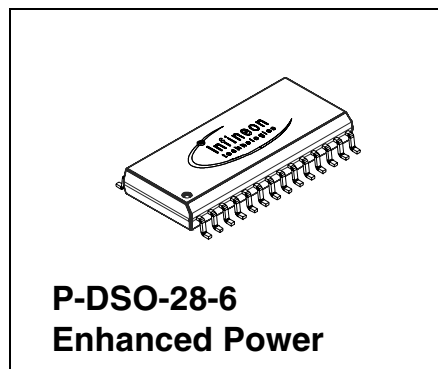


Preliminary Data Sheet
1 Overview
1.1 Features

- Standard fault tolerant differential CAN-transceiver
- Bus failure management
- Low power mode management
- Receive only mode for CAN
- CAN data transmission rate up to 125 kBaud
- Low-dropout voltage 5V regulator
- High side switch
- 2 wake-up inputs
- Power on and under-voltage reset generator
- Window watchdog
- Fail-safe output
- Early warning feature
- Standard 8 bit SPI-interface
- Wide input voltage range
- Wide temperature range
- Enhanced power P-DSO-Package



| Type | Ordering Code | Package |
|------------|---------------|------------|
| TLE 6263 G | Q67007-A9465 | P-DSO-28-6 |

Description

The TLE 6263 is a monolithic integrated circuit in an enhanced power P-DSO-28-6 package. The IC is optimized for use in advanced automotive electronic control units for body and convenience applications.

To support this applications the TLE 6263 covers the main smart power functions such as failure tolerant low speed CAN-transceiver for differential mode data transmission, low dropout voltage regulator (LDO) for internal and external 5V supply as well as a SPI (serial peripheral interface) to control and monitor the IC. Further there are integrated additional features like a high side switch that can be used e.g. for cyclic supply of an external wake-up circuitry, two wake-up inputs, a window watchdog circuit with fail safe output as well as a reset and early warning feature.

The IC is designed to withstand the severe conditions of automotive applications.

1.2 Pin Configuration (top view)

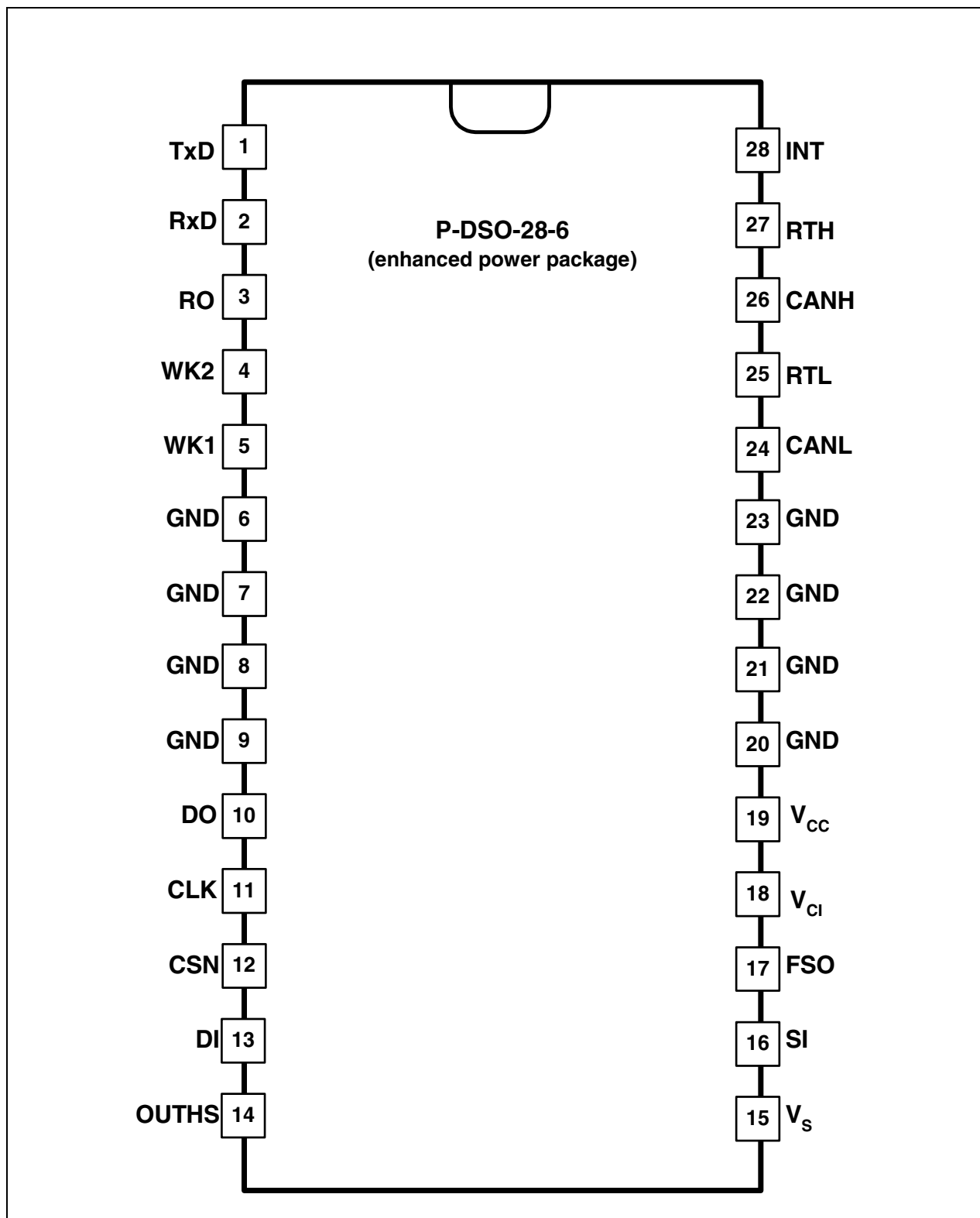


Figure 1

1.3 Pin Definitions and Functions

| Pin No. | Symbol | Function |
|----------------------------|--------|---|
| 1 | TxD | Transmit data input ; integrated pull up |
| 2 | RxD | Receive data output ; |
| 3 | RO | Reset output ; open drain output, integrated pull up, active low |
| 4 | WK2 | Wake-Up input 2 ; for detection of external wake-up events, level sensitive, in sleep mode monitored by cyclic sense feature when selected |
| 5 | WK1 | Wake-Up input 1 ; for detection of external wake-up events, edge sensitive, in sleep mode monitored by cyclic sense feature when selected |
| 6, 7, 8, 9, 20, 21, 22, 23 | GND | Ground ; to reduce thermal resistance place cooling areas on PCB close to this pins. |
| 10 | DO | SPI data output ; this tri-state output transfers diagnosis data to the control device; the output will remain 3-stated unless the device is selected by a low on Chip-Select-Not (CSN); see table 4, 5, 6 for Diagnosis protocol |
| 11 | CLK | SPI clock input ; clocks the shiftregister; CLK has an internal active pull down and requires CMOS logic level inputs |
| 12 | CSN | SPI chip select not input ; CSN is an active low input; serial communication is enabled by pulling the CSN terminal low; CSN input should only be transitioned when CLK is low; CSN has an internal active pull up and requires CMOS logic level inputs |
| 13 | DI | SPI data input ; receives serial data from the control device; serial data transmitted to DI is a 8 bit control word with the Least Significant Bit (LSB) being transferred first: the input has an active pull down and requires CMOS logic level inputs; DI will accept data on the falling edge of CLK-signal; see table 3 for input data protocol |
| 14 | OUTHS | High side switch output ; controlled via SPI, in sleep mode controlled by internal cyclic sense function when selected |
| 15 | Vs | Power supply input ; block to GND directly at the IC with ceramic capacitor |
| 16 | SI | Sense comparator input ; for monitoring of external voltages, to program the detection level connect external voltage divider |

1.3 Pin Definitions and Functions (cont'd)

| Pin No. | Symbol | Function |
|---------|-----------------|--|
| 17 | FSO | Fail safe output; to supervise and control critical applications, high when watchdog is correctly served, low at any reset condition, open drain output, internal pull up, active low |
| 18 | V _{CI} | Internal voltage supply; for stabilization of internal power supply, block to GND with an external capacitor $C_{VI} \geq 100 \text{ nF}$ |
| 19 | V _{CC} | Voltage regulator output; for 5V supply, to stabilize block to GND with an external capacitor $C_Q \geq 100 \text{ nF}$ |
| 24 | CANL | L bus line; LOW in dominant state |
| 25 | RTL | CANL-Termination output; connect to CANL bus line via termination resistor $500\Omega < R_{RTL} < 16k\Omega$ |
| 26 | CANH | H bus line; HIGH in dominant state |
| 27 | RTH | CANH-Termination input; connect to CANH bus line via termination resistor $500\Omega < R_{RTH} < 16k\Omega$ |
| 28 | INT | Interrupt output; to monitor wake-up events or valid sense input condition |

1.4 Functional Block Diagram

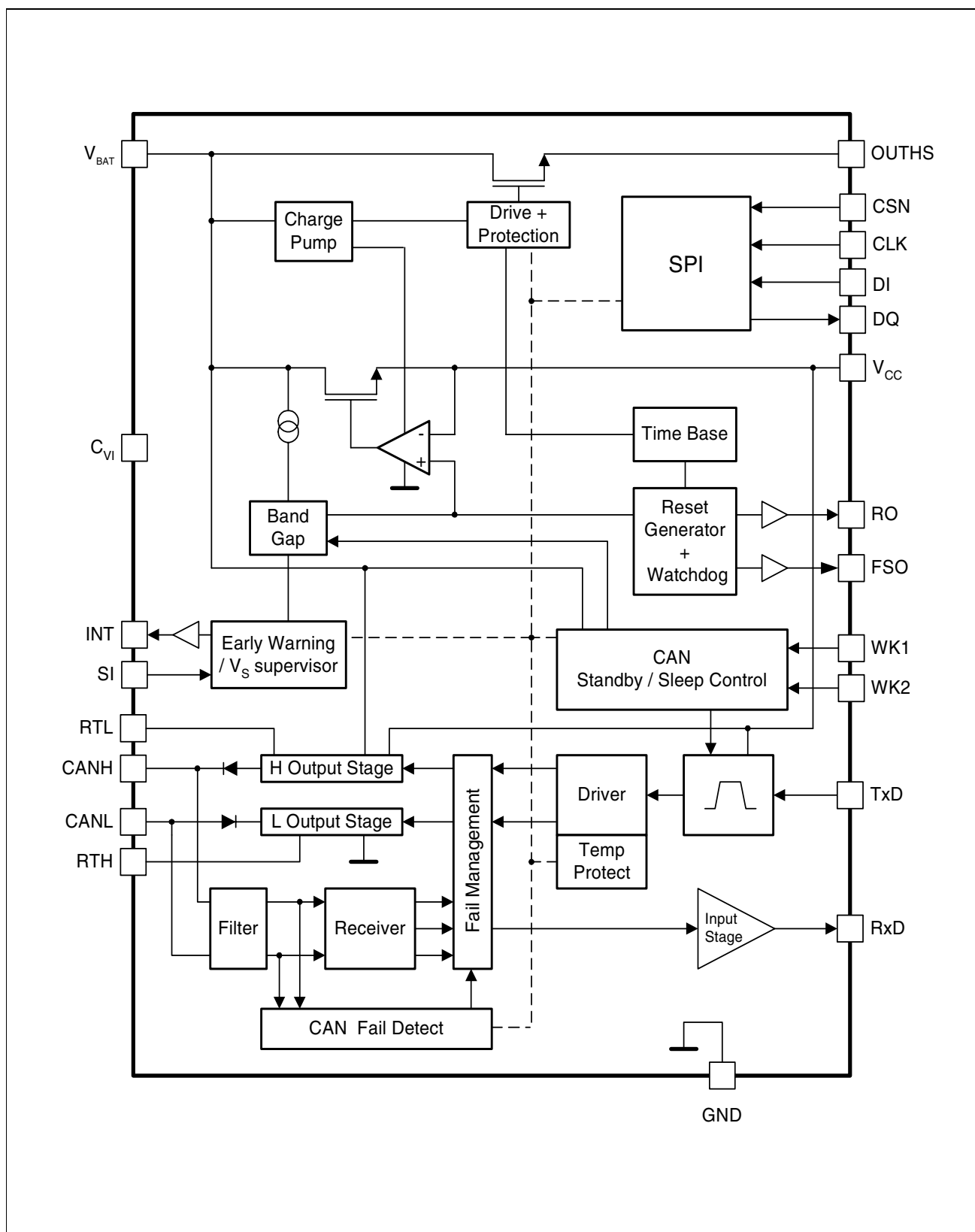


Figure 2

1.5 Circuit Description

The TLE 6263 is a monolithic IC, which incorporates a failure tolerant low speed CAN-transceiver for differential mode data transmission, a low dropout voltage regulator for internal and external 5V supply as well as a SPI (serial peripheral interface) to control and monitor the IC. Further there are integrated a high side switch, two wake-up inputs, a window watchdog circuit with fail safe output as well as a reset circuit and early warning function.

Figure 2 shows a block schematic diagram of the TLE 6263

Table 1: Truth table of the TLE 6263

| Feature | normal mode | receive-only mode | V _{bat} stand-by mode | sleep mode |
|--------------------------------------|--|--|--------------------------------|----------------------------|
| V _{CC} | ON | ON | ON | OFF |
| Reset | ON | ON | ON | OFF |
| Watchdog | ON | ON | ON ¹⁾ | OFF |
| Fail safe output | ON | ON | ON ⁵⁾ | OFF |
| V _{INT} -Fail ²⁾ | ON | ON | ON | ON |
| Sense input | ON | ON | ON | OFF |
| Wake-up 1 / 2 | ON ³⁾ | ON ³⁾ | ON | ON |
| HS-switch ⁴⁾ | ON | ON | ON | OFF |
| HS-cyclic-sense ⁴⁾ | OFF | OFF | ON | ON |
| SPI | ON | ON | ON | OFF |
| CAN transmit | ON | OFF | OFF | OFF |
| CAN receive | ON | ON | OFF | OFF |
| RTL output | switched to V _{cc} | switched to V _{cc} | switched to V _s | switched to V _s |
| RxD output | L = bus dominant; H = bus recessive | L = bus dominant; H = bus recessive | active low wake-up interrupt | low |
| INT output | active low early warning | active low early warning, V _{INT} and V _{CC} | active low early warning | low |

¹⁾ at low V_{CC} output current only active when watchdog undercurrent function is not activated

²⁾ monitored in V_{bat}-stand-by mode via SPI

³⁾ no wake-up interrupt generated, logic level status monitored via SPI

⁴⁾ only active when selected via SPI

⁵⁾ if watchdog under-current function active, than FSO = low

Operation Modes

The TLE 6263 offers four different operation modes that are controlled via the SPI interface: the normal operation mode, the receive-only mode, the V_{bat} stand-by mode and the sleep operation mode. Please see the state diagram (**figure 3**). Whereas in the normal operation mode both is possible, receiving and transmitting of messages, in the receive-only mode (RxD-only mode) the output stages are disabled which doesn't allow the CAN controller to send a message to the bus.

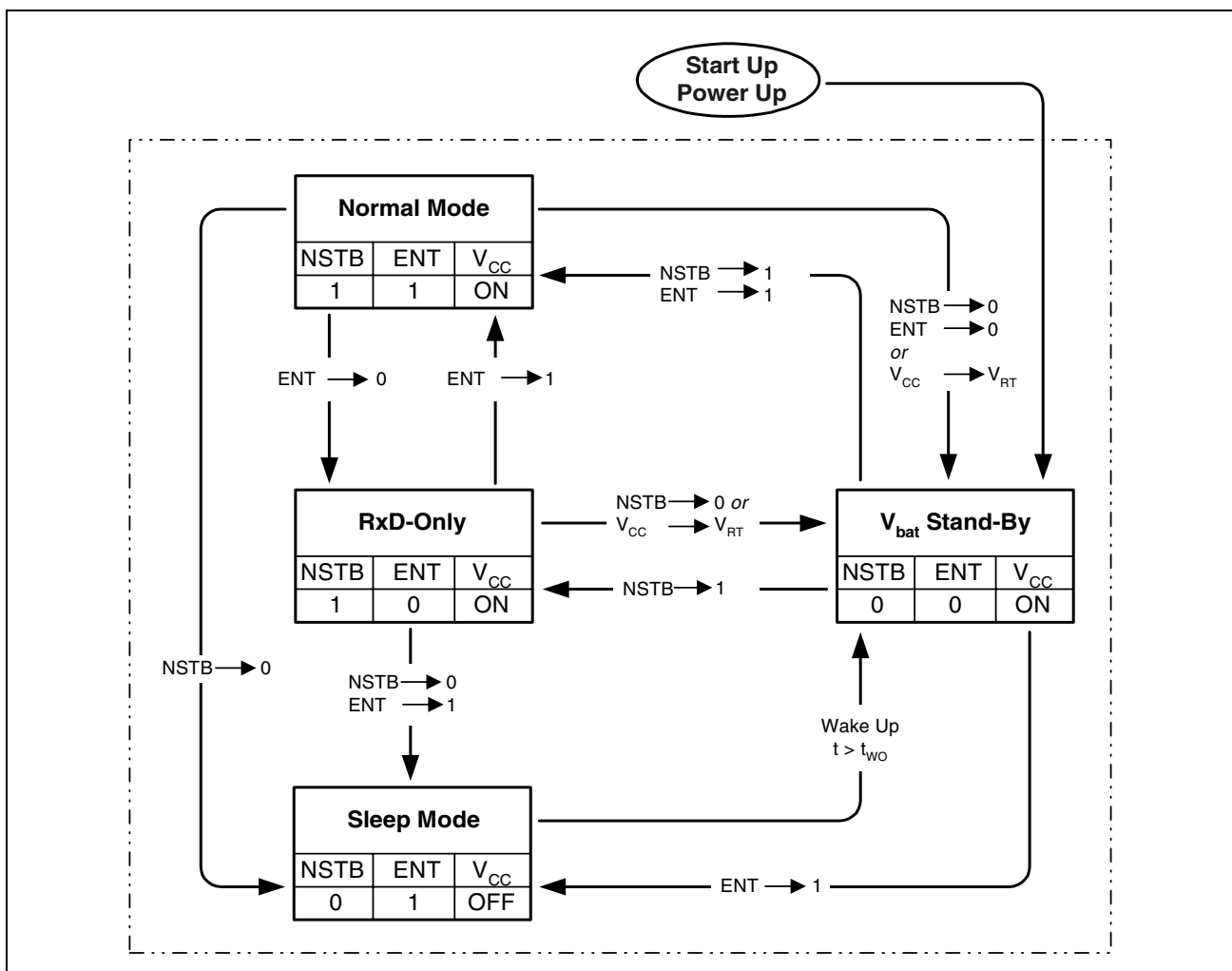


Figure 3: State Diagram

In the V_{bat} stand-by mode and sleep mode the RTL output voltage is switched to V_S . Both modes are low power modes. In the sleep mode the whole application is switched off by disabling the voltage regulator. That allows the total current consumption to drop down to less than 100 μA .

When a reset occurs due to false watchdog triggering the TLE6263 automatically switches from normal mode or receive-only mode respectively, to the V_{bat} stand-by mode. If a watchdog reset occurs in the V_{bat} stand-by mode the IC remains in this mode.

In sleep mode a wake-up at any of the wake-up inputs as well as via the bus lines (CANH or CANL) automatically sets the TLE 6263 in V_{bat} stand-by mode. In the V_{bat} stand-by mode a wake-up is monitored by setting the output RxD low. To send and to receive messages the CAN-transceiver now has to be set to normal operation mode by the microcontroller. In case the IC shall directly be set back to sleep mode after a wake-up, an internal wake-flip-flop has to be reset via the SPI. Therefore IBIT1 has to be set high and then low again by a second SPI transmission. A transition from the V_{bat} stand-by mode to the normal mode or receive-only mode respectively, automatically resets the wake-flip-flop.

Low Dropout Voltage Regulator

The low dropout voltage regulator integrated in the TLE 6263 is able to drive the internal loads (e.g. CAN-circuit) as well as external 5V loads. Its output voltage tolerance is better than $\pm 2\%$. The maximum output current is limited to 110 mA.

An external reverse current protection is recommended at the pin Vs to prevent the output capacitor from being discharged by negative transients or low input voltage.

Stability of the output voltage is guaranteed for output capacitors $C_Q \geq 100$ nF, nevertheless it is recommended to use capacitors $C_Q \geq 10$ μ F to buffer the output voltage and therefore improve the reset behavior at input voltage transients.

To stabilize the internal supply a capacitor $C_{V1} \geq 100$ nF directly connected to the pin V_{C1} is required.

CAN Transceiver

The TLE 6263 is optimized for low speed data transmission up to 125 kBaud in automotive applications. Normally a differential signal is transmitted and received respectively. When a bus wiring failure (see **table 2**) is detected the device automatically switches to a dedicated CANH or CANL single-wire mode to maintain the communication if necessary. Therefore it is equipped with one differential receiver and four single ended comparators (two for each bus line). To avoid false triggering by external RF influences the single wire modes are activated after certain delay times. As soon as the bus failure disappears the transceiver switches back to differential mode after another time delay. The bus failures are monitored via the diagnosis protocol of the SPI. It is possible to distinguish between six CAN bus failures or bus failure groups on the bits 2 to 7 (see **table 4 and 5**).

To reduce EMI the dynamic slopes of the CANL and CANH signals are both limited and symmetric. This allows the use of an unshielded twisted or parallel pair of wires for the bus. During single-wire transmission (bus-failure) the EMI performance of the system is degraded from the differential mode.

The differential receiver threshold is set to typ. -2.5 V. This ensures correct reception in the normal operation mode as well as in the failure cases 1, 2, 3a and 4 with a noise margin as high as possible.

Table 2, CAN bus line failure cases (according to ISO 11519-2)

| failure # | failure description |
|---------------------|---|
| 1 | CANL line interrupted |
| 2 | CANH line interrupted |
| 3 | CANL shorted to Vbat, $CANL > 7.2\text{ V}$ |
| 3a (no ISO failure) | CANL shorted to Vcc; $3.2\text{ V} < CANL < 7.2\text{ V}$ |
| 4 | CANH shorted to GND |
| 5 | CANL shorted to GND |
| 6 | CANH shorted to Vbat; $CANH > 7.2\text{ V}$ |
| 6a (no ISO failure) | CANH shorted to Vcc; $1.8\text{ V} < CANH < 7.2\text{ V}$ |
| 7 | CANL shorted to CANH |

When one of the bus failures 3, 5, 6, 6a, and 7 is detected, the defective bus wire is disabled by switching off the affected bus termination and output stage. Simultaneously the multiplexing output of the receiver circuit is switched to the unaffected single ended comparator.

Furthermore there is implemented a time-out feature to prevent the bus from being blocked by a permanently dominant TxD input signal. Both, the CANL and CANH output stage are automatically disabled after the delay time t_{TxD} .

In order to protect the transceiver output stages from being damaged by shorts on the bus lines, current limiting circuits are integrated. The CANL and CANH output stage respectively are protected by an additional temperature sensor, that disables them as soon as the junction temperature exceeds the maximum value. In the temperature shut-down condition of the CAN output stages receiving messages from the bus lines is still possible.

SPI (serial peripheral interface)

The 8-bit wide programming word (input word, see **table 3**) is read in via the data input DI, and this is synchronized with the clock input CLK supplied by the μ C. The diagnostic information depends on the operation mode. The internal latches for the V_{bat} -stand-by diagnosis are reseted when leaving this mode.

The transmission cycle begins when the TLE6263 is selected by the chip select not input CSN (H to L). After the CSN input returns from L to H, the word that has been read in becomes the new control word. The DO output switches to tri-state status at this point, thereby releasing the DO bus circuit for other uses. For details of the SPI timing please refer to **figure 4 to 7**.

Table 3, Input Data Protocol
all modes

| IBIT | |
|------|--|
| 7 | Watchdog Undercurrent Control |
| 6 | Set V_{INT} -Fail + V_{CC} Fail Flag |
| 5 | OUTHS ON |
| 4 | OUTHS Cyclic Sense |
| 3 | Not Standby |
| 2 | Enable Transmit |
| 1 | Reset Internal WK-FF |
| 0 | Watchdog Trigger |

H = ON
L = OFF

Table 4, Diagnosis Data Protocol
normal mode

| OBIT | |
|------|------------------------|
| 7 | HS UV / Temp-Shut Down |
| 6 | HS Overcurrent |
| 5 | CANL bus fail |
| 4 | CANH bus fail |
| 3 | WK2 logic level |
| 2 | WK1 logic level |
| 1 | Window Watchdog Reset |
| 0 | Temperature Prewarning |

H = ON
L = OFF

Table 5, Diagnosis Data Protocol
RxD-only mode

| OBIT | |
|------|------------------------|
| 7 | CAN Failure 5 and 7 |
| 6 | CAN Failure 6 |
| 5 | CAN Failure 6a |
| 4 | CAN Failure 2 and 4 |
| 3 | CAN Failure 3 |
| 2 | CAN Failure 1 and 3a |
| 1 | Window Watchdog Reset |
| 0 | Temperature Prewarning |

H = ON
L = OFF

Table 6, Diagnosis Data Protocol
 V_{bat} -Stand-by mode

| OBIT | |
|------|---------------------------|
| 7 | V_{CC} Not-Fail |
| 6 | V_{INT} Not-Fail |
| 5 | WK1/2 Initialization Fail |
| 4 | Wake via CAN bus lines |
| 3 | WK2 voltage level |
| 2 | WK1 voltage level |
| 1 | Window Watchdog Reset |
| 0 | Temperature Prewarning |

H = ON
L = OFF

Window Watchdog, Reset

When the input voltage exceeds the reset threshold voltage the reset output RO is switched HIGH after a delay time of typ. 8ms. This is necessary for a defined start of the microcontroller when the application is switched on. As soon as an under-voltage condition of the output voltage ($V_{CC} < V_{RT}$) appears, the reset output RO is switched LOW again. The LOW signal is guaranteed down to an output voltage $V_Q \geq 1V$. Please refer to **fig. 9**, reset timing diagram.

After the above described delayed reset (LOW to HIGH transition of RO) the window watchdog circuit is started by opening a long open window of typ. 65ms. The long open window allows the microcontroller to run his set-up and then to trigger the watchdog via the SPI. Within the long open window period a watchdog trigger is detected as a “rising edge” by sampling a HIGH on the IBIT 0. The trigger is accepted when the CSN input becomes HIGH after the transmission of the SPI word. After each reset as well as after a power on condition the default value of IBIT 0 is LOW.

A correct watchdog trigger results in starting the window watchdog by opening a closed window of typ. 6 ms followed by a open window of typ. 10 ms. From now on the microcontroller has to service the watchdog trigger by inverting the IBIT 0 alternating. The “negative” or “positive” edge has to meet the open window time. A correct watchdog

service immediately results in starting the next closed window. Please refer to **fig. 10**, watchdog timing diagram.

Should the trigger signal not meet the open window a watchdog reset is created by setting the reset output RO low for a period of typ. 2 ms. Then the watchdog again starts by opening a long open window. In addition, the SPI OBIT 1 (diagnosis bit 1) is set HIGH until the next successful watchdog trigger to monitor a watchdog reset. OBIT1 is also HIGH until the watchdog is correctly triggered after power-up / start-up. For fail safe reasons the TLE6263 is automatically switched in Vbat-stand-by mode if a watchdog trigger failure occurs. By this the power consumption can be minimized in case of a permanent faulty microcontroller.

In case of either an undervoltage reset or a watchdog reset all SPI input registers (IBIT 0 to IBIT 7) are set low.

To avoid cyclic wake-up's of the microcontroller due to missing watchdog pulses when the microcontroller is in a low power mode, an automatic undercurrent disabling function of the watchdog circuit can be selected for the TLE 6263 Vbat-stand-by mode. For activation of this feature, the V_{CC} output current in the Vbat-stand-by mode has to be less than the undercurrent threshold ($I_{CC} < I_{CCWD}$) and in addition the SPI IBIT 7 has to be set HIGH. When the microcontroller returns back to normal mode or the output current becomes higher than $I_{CC} > I_{CCWD}$ the watchdog circuit is enabled again. A long open window is started then, to ensure a simple synchronization of the watchdog timing to the watchdog services of the microcontroller.

In sleep operation mode, the watchdog circuit is automatically disabled.

Flash program mode

To disable the watchdog feature a flash program mode is available. This mode is selected by applying a voltage of $6.8V < V_{INT} < 7.2V$ at pin INT. This is useful e.g. if the flash-memory of the micro has to be programmed and therefore a regular watchdog triggering is not possible. If the SPI is required in the flash program mode to change e.g. the mode of the TLE6263 the first input telegram has to be "00000000".

Fail Safe feature

The output FSO becomes HIGH when the watchdog is correctly serviced by the microcontroller for the fourth time. As soon as either an under-voltage reset or watchdog reset occurs, it is set LOW again. This feature is very useful to control critical applications independent of the due function of the microcontroller e.g. to disable the power supply in case of a microcontroller failure.

Sense Comparator (pin SI) and V_{INT} -fail

The sense comparator (early warning function) compares a voltage defined by the user to an internal reference voltage. Therefore the voltage to be supervised has to be scaled down by an external voltage divider in order to compare it to the internal sense threshold V_{SIth} . This feature can be used e.g. to supervise the battery voltage in front of the reverse protection diode. The microcontroller is given a pre-warning before an under-voltage reset due to low input voltage occurs. The pre-warning is flagged by setting the interrupt output INT low in normal mode, receive only mode and V_{bat} -stand-by mode. In sleep operation mode the sense function is inactive.

Calculation of the voltage divider can be easily done since the sense input current can be neglected. An internal blanking time prevents from false triggering due to line transients. Further improvement is possible by the use of an external ceramic capacitor in parallel to R2 (see application circuit **fig.12**).

To activate the V_{INT} supervisor feature the SPI IBIT 6 has to be set HIGH to set an internal flip-flop. This automatically sets the V_{bat} -stand-by OBIT 6 HIGH, too. Should the internal supply voltage become lower than the internal threshold $V_{VINT,th}$ the NOT V_{INT} -Fail bit becomes LOW to indicate the low voltage condition. All SPI input registers are set LOW due to a low voltage condition of the internal supply voltage.

Like the wake-up diagnosis the V_{INT} -Fail diagnosis can only be monitored in the V_{bat} -stand-by mode.

The V_{INT} -Fail feature can also be used to give an indication when the ECU has been changed and therefore a pre-setting routine of the microcontroller has to be started.

Further to the reset threshold there is implemented another supervisor threshold for the output voltage V_{CC} . It's typical threshold is 2.5V. The NOT V_{CC} -Fail feature is monitored via OBIT 7 in the V_{bat} stand-by mode and set like the NOT V_{CC} -Fail Flag via IBIT 6.

In the receive-only mode both Fail bits cause the interrupt output INT to go low.

Wake-Up Inputs WK1, WK2

In addition to a wake-up from sleep mode via the bus lines CANH or CANL it is also possible to wake-up the TLE6263 from low power mode via the wake-up inputs WK1 and WK2. The wake-up inputs are sensitive to a transition of the voltage level, either from high to low or the other way round. They are active in all operation modes. In the normal mode the current logic level at WK1/2 is monitored via the SPI (see **table 4 and 6**).

A positive or negative voltage edge at WK1/2 in V_{bat} -stand-by mode or sleep mode immediately results in setting the output RxD low to signal a wake-up. After a wake-up via WK1/2 the transmission of the SPI diagnosis word in the V_{bat} -stand-by mode shows the logic level that has caused the wake-up. To get the current voltage levels at WK1/2

in the V_{bat} -stand-by mode the internal wake flip-flop has to be reseted by the IBIT1 for each transmission. As long as IBIT1 is set high or the internal wake flip-flop is reseted respectively, in the V_{bat} -stand-by mode the RxD output is blocked to signal a new wake-up event via the CAN-bus or the wake-up inputs.

Further to the continues sensing at the wake-up inputs a cyclic sense feature is possible. When the OUTHS cyclic sense feature is selected via the SPI IBIT 4 the high side switch as well as the WK1/2 inputs are periodically activated by the TLE6263 in the sleep and V_{bat} -stand-by mode.

When switching the TLE6263 into sleep mode (cyclic sense feature activated) the voltage level at the wake-inputs is sensed 2 times to initialize the reference voltage. Should this initialisation fail (2 samples are unequal) the device is automatically set in V_{bat} -stand-by mode and the initialisation error is shown on the OBIT 5. To enter the sleep mode now directly from the V_{bat} -stand-by mode, the internal wake flip-flop has to be reseted by the IBIT 1.

Interrupt output INT

Like the reset output, the interrupt output is a low active output. It is used to monitor low voltage conditions at the sense input in normal mode and stand-by mode (see **table 8**). In the receive-only mode the V_{INT} -fail flag and V_{CC} supervisor are monitored.

High Side Switch

The high side output OUTHS is able to switch loads up to 150 mA. Its on-resistance is $1.0\ \Omega$ typ. @ 25°C . This switch is controlled via the SPI input bits 4 and 5. In normal mode, receive-only mode and V_{bat} -stand-by mode the high side output is switched on and off, respectively via the SPI input bit 5.

To supply external wake-up circuits in sleep mode and V_{bat} -stand-by mode the output OUTHS can be periodically switched on by the TLE6263 itself. In order to activate this cyclic sense feature the SPI IBIT 4 has to be set high. The auto-timing period then is typ. 65 ms, the on-time is typ. 1 ms. Should there be any over-current condition at the switch in the sleep mode (cyclic sense activated) or V_{bat} -stand-by mode a wake-up is flagged via the RxD output. The over-current condition is monitored on the SPI OBIT 6 in normal operation mode.

The SPI OBIT 0 flags a thermal pre-warning of the high side switch. By this the microcontroller is able to reduce the power dissipation of the TLE6263 by switching off functions of minor priority until the temperature threshold of the thermal shutdown is reached. Further OUTHS is protected against short circuit and overload. As soon as the under-voltage condition of the supply voltage is met ($V_S < V_{UVOFF}$), the switch is

automatically disabled by the under-voltage lockout circuit. Moreover the switch is automatically disabled when a reset or watchdog reset occurs.

Hints for unused pins

SI: connect to V_S

OUTHS: leave open

WK1/2: connect to V_S or leave open

INT: leave open

RO: leave open

FSO: leave open

2 Electrical Characteristics

2.1 Absolute Maximum Ratings

| Parameter | Symbol | Limit Values | | Unit | Remarks |
|-----------|--------|--------------|------|------|---------|
| | | min. | max. | | |

Voltages

| | | | | | |
|--|---------------|-------|----------------|---|--|
| Supply voltage | V_S | -0.3 | 28 | V | |
| Supply voltage | V_S | -0.3 | 40 | V | $t_p < 0.5s$; $t_p/T < 0.1$ |
| Regulator output voltage | V_{CC} | -0.3 | 5.5 | V | |
| CAN bus voltage (CANH, CANL) | $V_{CANH/L}$ | -20 | 28 | V | |
| CAN bus voltage (CANH, CANL) | $V_{CANH/L}$ | -40 | 40 | V | $V_S > 0 V$ $t_p < 0.5s$; $t_p/T < 0.1$ |
| Logic input voltages (DI, CLK, CSN, OSC, TxD) | V_I | -0.3 | $V_{CC} + 0.3$ | V | $0 V < V_S < 24 V$ $0 V < V_{CC} < 5.5 V$ |
| Logic output voltage (DO, RO, INT, RxD, FSO) | $V_{DRI, RD}$ | -0.3 | $V_{CC} + 0.3$ | V | $0 V < V_S < 24 V$ $0 V < V_{CC} < 5.5 V$ |
| Termination input voltage (RTH, RTL) | $V_{TL/TH}$ | -0.3 | $V_S + 0.3$ | V | $0 V < V_S < 24 V$ $0 V < V_{CC} < 5.5 V$ |
| Input voltages at WK1/2 and SI | $V_{WK/SI}$ | -40 | 40 | V | |
| Electrostatic discharge voltage at pin CANH, CANL, SI, V_S | V_{esd} | -4000 | 4000 | V | human body model, $C = 100 pF$, $R = 1.5 k\Omega$ |
| Electrostatic discharge voltage at any other pin | V_{esd} | -2000 | 2000 | V | human body model, $C = 100 pF$, $R = 1.5 k\Omega$ |

Currents

| | | | | | |
|--------------------------|-------------|----|-----|---|-----------------------|
| Output current; V_{CC} | I_{CC} | — | — | A | internally limited |
| Output current; OUTHS | I_{OUTH1} | *) | 0.2 | A | *) internally limited |

2.1 Absolute Maximum Ratings (cont'd)

| Parameter | Symbol | Limit Values | | Unit | Remarks |
|----------------------|-----------|--------------|------|------|---------|
| | | min. | max. | | |
| Temperatures | | | | | |
| Junction temperature | T_j | – 40 | 150 | °C | – |
| Storage temperature | T_{stg} | – 50 | 150 | °C | – |

Note: Maximum ratings are absolute ratings; exceeding any one of these values may cause irreversible damage to the integrated circuit.

2.2 Operating Range

| Parameter | Symbol | Limit Values | | Unit | Remarks |
|---|-----------|---------------|----------|------------|---------------------------------------|
| | | min. | max. | | |
| Supply voltage | V_S | $V_{UV\ OFF}$ | 20 | V | After V_S rising above $V_{UV\ ON}$ |
| Supply voltage | V_S | $V_{UV\ OFF}$ | 40 | V | thermally limited |
| Supply voltage slew rate | dV_S/dt | -0.5 | 5 | V/ μ s | |
| Logic input voltage (DI, CLK, CSN, TxD) | V_I | - 0.3 | V_{CC} | V | |
| Output capacitor | C_{CC} | 100 | | nF | |
| Output capacitor | C_{VI} | 100 | 460 | nF | |
| SPI clock frequency | f_{clk} | | 1.5 | MHz | |
| Junction temperature | T_j | - 40 | 150 | °C | |

Thermal Resistances

| | | | | | |
|------------------|---------------|---|----|-----|--|
| Junction pin | $R_{thj-pin}$ | — | 25 | K/W | |
| Junction ambient | R_{thj-a} | — | 65 | K/W | |

2.3 Electrical Characteristics

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ °C} < T_j < 150\text{ °C}$ (max. 125 °C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|-----------|--------|--------------|------|------|------|----------------|
| | | min. | typ. | max. | | |

Quiescent current Pin V_S

| | | | | | | |
|---|-------|---|-------|-----|----|---|
| Current consumption $I_Q = I_S - I_{CC}$ | I_Q | – | t.b.d | | mA | normal mode; $I_{CC} = 30\text{ mA}$; TxD recessive |
| Current consumption $I_Q = I_S - I_{CC}$ | I_Q | – | t.b.d | | mA | normal mode; $I_{CC} = 30\text{ mA}$; TxD dominant |
| Current consumption $I_Q = I_S - I_{CC}$ | I_Q | – | 300 | 400 | μA | stand-by mode; $T_j = 25\text{ °C}$; $I_{CC} = 1\text{ mA}$; Ibit 7 = H |
| Current consumption | I_Q | – | 60 | 100 | μA | sleep mode; $T_j = 25\text{ °C}$; SPI Ibit 4 = H/L; $V_{CC} = V_{CCI} = 0\text{ V}$ |
| Current consumption | I_Q | | | 3 | mA | OUTHS active; SPI Ibit 4 = H; sleep mode; $T_j = 25\text{ °C}$; $V_{CC} = V_{CCI} = 0\text{ V}$ |

Voltage Regulator; Pin V_{CC}

| | | | | | | |
|---|-----------------|-----|------|-----|----|---|
| Output voltage | V_{CC} | 4.9 | 5.0 | 5.1 | V | $0.1\text{ mA} < I_{CC} < 100\text{ mA}$ $6\text{ V} < V_I < 20\text{ V}$ |
| Output voltage | V_{CC} | 4.8 | 5.00 | 5.5 | V | $0\text{ A} < I_{CC} < 100\text{ μA}$ |
| Line regulation | ΔV_{CC} | | | 50 | mV | $6\text{ V} < V_S < 16\text{ V}$; $I_{CC} = 1\text{ mA}$ |
| Load regulation | ΔV_{CC} | | | 50 | mV | $5\text{ mA} < I_{CC} < 100\text{ mA}$; $V_S = 6\text{ V}$ |
| Power supply ripple rejection | $PSRR$ | | 40 | | dB | $V_S < 1\text{ Vss}$; $C_Q \geq 10\text{ μF}$ $100\text{ Hz} < f < 100\text{ kHz}$ |
| Output current limit | I_{CCmax} | 110 | 120 | | mA | note 1) |
| Output current limit | I_{CCmax} | | 120 | | mA | $V_{CC} = 0\text{ V}$ |
| Drop voltage $V_{DR} = V_S - V_{CC}$ | V_{DR} | | | 0.5 | V | $I_{CC} = 80\text{ mA}$; note 1) |

note 1) measured when the output voltage V_{CC} has dropped 100 mV from the nominal value obtained at 13.5 V input voltage V_S

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ }^{\circ}\text{C} < T_J < 150\text{ }^{\circ}\text{C}$ (max. 125°C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|-----------|--------|--------------|------|------|------|----------------|
| | | min. | typ. | max. | | |

Oscillator

| | | | | | | |
|---|-----------|------|------|------|-----|------------|
| internal oscillating frequency | f_{OSC} | | 125 | | kHz | |
| Internal cycling time ($1/64 * f_{OSC}$) ⁻¹ | t_{CYL} | 0.43 | 0.51 | 0.59 | ms | |
| Internal cycling time ($1/64 * f_{OSC}$) ⁻¹ | t_{CYL} | 0.30 | 0.51 | 0.72 | ms | sleep mode |

Reset Generator; Pin RO

| | | | | | | |
|----------------------------|----------|-----|------|----------------|---------------|---|
| Reset threshold voltage | V_{RT} | 4.5 | 4.65 | 4.8 | V | V_{CC} decreasing |
| Reset low output voltage | V_{RO} | | 0.2 | 0.4 | V | $I_{RO} = 1\text{ mA}$ for $V_{CC} = V_{RT}$ or $I_{RO} = 200\text{ }\mu\text{A}$ for $V_{CC} \geq 1\text{ V}$ |
| Reset high output voltage | V_{RO} | 4.0 | | $V_{CC} + 0.1$ | V | |
| Reset pull up current | I_{RO} | 20 | 150 | 500 | μA | $V_{RO} = 0\text{ V}$ |
| Reset reaction time | t_{RR} | 1 | 3 | 10 | μs | $V_{CC} < V_{RT}$ to $RO = L$ |
| Reset delay time (16 cyl.) | t_{RD} | 6.9 | 8.2 | 9.5 | ms | |

Watchdog Generator

| | | | | | | |
|--|------------|-----|------|------|----|--|
| Watchdog trigger | t_{WD} | 7.2 | 10 | 13.6 | ms | |
| Long open window (128 cyl.) | t_{CW} | 55 | 65 | 76 | ms | |
| Closed window (12 cyl.) | t_{CW} | 5.1 | 6.1 | 7.1 | ms | |
| Open window (20 cyl.) | t_{OW} | 8.6 | 10.2 | 11.8 | ms | |
| Watchdog reset-puls time (4 cyl.) | t_{WDR} | 1.7 | 2.0 | 2.4 | ms | |
| Watchdog undercurrent disable threshold | I_{CCWD} | 1.5 | 4 | 7 | mA | $T_J < 85\text{ }^{\circ}\text{C}$; Watchdog OFF when $I_{CC} < I_{CCWD}$ and SPI- lbit 7= H |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ °C} < T_j < 150\text{ °C}$ (max. 125 °C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|--|---------------|--------------|------|------|------|----------------|
| | | min. | typ. | max. | | |
| Watchdog Undercurrent disable hysteresis | $I_{CCWDhys}$ | | 0.5 | | mA | |
| Watchdog Undercurrent reaction time | t_{LHR} | | 25 | | μs | |

Fail Safe Output; Pin FSO

| | | | | | | |
|--|----------|-----|-----|----------------|---|---|
| Watchdog edge count difference to set HIGH | n_{FS} | | 4 | | V | |
| Fail Safe low output voltage | V_{FS} | | 0.2 | 0.4 | V | $I_{FSO} = 1\text{ mA}$ for $V_{CC} = V_{RT}$ or $I_{FSO} = 200\text{ μA}$ for $V_{CC} \geq 1\text{ V}$ |
| Fail Safe high output voltage | V_{FS} | 4.0 | | $V_{CC} + 0.1$ | V | $I_{FSO} = -1\text{ mA}$ for $V_{CC} \geq V_{RT}$ |

Sense Input (Early Warning) SI, V_{INT} -Fail, Interrupt Output INT

| | | | | | | |
|-----------------------------------|---------------|---------------------|-----|----------|----|--|
| Sense In threshold voltage | $V_{SI,th}$ | | 2.3 | | V | V_{SI} decreasing |
| Sense In threshold hysteresis | $V_{SI,hys}$ | | 200 | | mV | |
| Sense Input Current | I_{SI} | | 0.1 | | μA | $V_{SI} \geq 0\text{ V}$ |
| Sense reaction time | $t_{S,r}$ | 5 | 10 | 20 | μs | $V_S < V_{S,th}$ to INT = low |
| Interrupt Out high voltage | $V_{INThigh}$ | $0.7 \times V_{CC}$ | – | V_{CC} | V | $I_0 = -250\text{ μA}$ |
| Interrupt Out low voltage | V_{INTlow} | 0 | – | 0.9 | V | $I_0 = 1.25\text{ mA}$ |
| Interrupt pull up current | I_{INT} | 20 | 150 | 500 | μA | $V_{INT} = 0\text{ V}$ |
| V_{CC} -Fail threshold voltage | $V_{VCC,th}$ | 2.3 | 2.7 | 3.1 | V | |
| V_{CC} -Fail reaction time | $t_{VCC,r}$ | | 5 | | μs | $V_{CC} < V_{VCC,th}$ to Obi 6 = low; V_{bat} -stand-by mode |
| V_{INT} -Fail threshold voltage | $V_{VINT,th}$ | 2.0 | 2.4 | t.b.d. | V | |
| V_{INT} -Fail reaction time | $t_{VINT,r}$ | | 20 | | μs | Obi 7 = low; V_{bat} -stand-by mode |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ }^{\circ}\text{C} < T_J < 150\text{ }^{\circ}\text{C}$ (max. 125°C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|-----------|--------|--------------|------|------|------|----------------|
| | | min. | typ. | max. | | |

Wake-Up Inputs WK1 / WK2

| | | | | | | |
|---------------------------|------------|----|----|----|---------------|--------------------------------|
| Wake-up threshold voltage | V_{WUth} | 2 | 3 | 4 | V | sleep mode; Vbat-stand-by mode |
| Minimum time for wake-up | t_{WU} | 12 | 20 | 32 | μs | sleep mode; Vbat-stand-by mode |
| Input current | I_{WK} | | -2 | | μA | $V_{WK} = 0\text{ V}$ |

High Side Output OUTHS; (controlled by bit 4 and bit 5 of SPI input word)

| | | | | | | |
|--|-----------------|-------|------|------|---------------|---|
| Static Drain-Source ON-Resistance; $I_{OUTH3} = -0.15\text{ A}$ | $R_{DS(on) HS}$ | — | 1.0 | 1.5 | Ω | $T_J = 25\text{ }^{\circ}\text{C}$ |
| | | | — | 3.0 | Ω | |
| | | | 2.5 | 3.0 | Ω | $5.2\text{ V} \leq V_S \leq 9\text{ V}$ $T_J = 25\text{ }^{\circ}\text{C}$ |
| | | | — | 5.0 | Ω | $5.2\text{ V} \leq V_S \leq 9\text{ V}$ |
| Active zener voltage | V_{OUTH3} | | -3 | | V | $I_{OUTH3} = -0.15\text{ A}$ |
| Clamp diode forward voltage | V_{OUTH3} | | | 1 | V | $I_{OUTH3} = 0.15\text{ A}$ |
| Leakage current | I_{QLHS} | t.b.d | | | μA | $V_{OUTH3} = 0\text{ V}$ |
| Switch ON delay time | t_{dONHS} | | | 100 | μs | CSN high to OUTHS |
| Switch OFF delay time | t_{dOFFHS} | | | 100 | μs | CSN high to OUTHS |
| Overcurrent shutdown threshold | I_{SDHS} | -0.8 | -0.4 | -0.2 | A | — |
| Shutdown delay time | t_{dSDHS} | 10 | 25 | 40 | μs | |
| Current limit | I_{OCLHS} | -1.2 | -0.6 | -0.3 | A | |
| UV-Switch-ON voltage | $V_{UV ON}$ | — | 5.35 | 6.00 | V | V_S increasing |
| UV-Switch-OFF voltage | $V_{UV OFF}$ | 4.50 | 4.85 | 5.20 | V | V_S decreasing |
| UV-ON/OFF-Hysteresis | $V_{UV HY}$ | — | 0.5 | — | V | $V_{UV ON} - V_{UV OFF}$ |
| Cyclic sense period (128 cyl.) | $t_{P CS}$ | 38 | 65 | 92 | ms | sleep mode SPI-bit 4 = H, |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ °C} < T_j < 150\text{ °C}$ (max. 125 °C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|-----------------------------------|--------------------|--------------|------|------|------|--|
| | | min. | typ. | max. | | |
| Cyclic sense period (128 cyl.) | $t_{P\text{ CS}}$ | 55 | 65 | 76 | ms | Vbat-stand-by mode; SPI-bit 4 = H; watchdog under- current feature active |
| Cyclic sense ON time (2 cyl.) | $t_{CS\text{ on}}$ | | 1 | | ms | |

CAN-Transceiver

Receiver Output R×D

| | | | | | | |
|---------------------------|----------|----------------|--|----------|---|---------------------------------|
| HIGH level output voltage | V_{OH} | $V_{CC} - 0.9$ | | V_{CC} | V | $I_0 = -250\text{ }\mu\text{A}$ |
| LOW level output voltage | V_{OL} | 0 | | 0.9 | V | $I_0 = 1.25\text{ mA}$ |

Transmission Input T×D

| | | | | | | |
|---------------------------------------|----------|---------------------|----------------------|---------------------|---------------|--------------------|
| HIGH level input voltage threshold | V_{IH} | | $0.52 \times V_{CC}$ | $0.7 \times V_{CC}$ | V | |
| LOW level input voltage threshold | V_{IL} | $0.3 \times V_{CC}$ | $0.48 \times V_{CC}$ | | V | |
| HIGH level input current | I_{IH} | -150 | -40 | -10 | μA | $V_i = 4\text{ V}$ |
| LOW level input current | I_{IL} | -600 | -200 | -40 | μA | $V_i = 1\text{ V}$ |

Bus Lines CANL, CANH

| | | | | | | |
|---|--------------|------|------|------|---|--|
| Differential receiver recessive-to-dominant threshold voltage | V_{dRxDrD} | -2.8 | -2.5 | -2.2 | V | |
| Differential receiver dominant-to-recessive threshold voltage | V_{dRxDdr} | -3.1 | -2.9 | -2.5 | V | |
| CANH recessive output voltage | V_{CANHr} | 0.1 | 0.2 | 0.3 | V | $TxD = V_{CC}$; $R_{RTH} < 4\text{ k}\Omega$ |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ °C} < T_j < 150\text{ °C}$ (max. 125 °C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|---|---------------|----------------|----------------|----------|---------------|--|
| | | min. | typ. | max. | | |
| CANL recessive output voltage | V_{CANLr} | $V_{CC} - 0.2$ | | | V | $TxD = V_{CC}$; $R_{RTL} < 4\text{ k}\Omega$ |
| CANH dominant output voltage | V_{CANHd} | $V_{CC} - 1.4$ | $V_{CC} - 1.0$ | V_{CC} | V | $TxD = 0\text{ V}$; $I_{CANH} = -40\text{ mA}$ |
| CANL dominant output voltage | V_{CANLd} | | 1.0 | 1.4 | V | $TxD = 0\text{ V}$; $I_{CANL} = 40\text{ mA}$ |
| CANH output current | I_{CANH} | -110 | -80 | -50 | mA | $V_{CANH} = 0\text{ V}$; $TxD = 0\text{ V}$ |
| | | -5 | 0 | 5 | μA | sleep mode; $V_{CANH} = 12\text{ V}$ |
| CANL output current | I_{CANL} | 50 | 80 | 110 | mA | $V_{CANL} = 5\text{ V}$; $TxD = 0\text{ V}$ |
| | | -5 | | 5 | μA | sleep mode; $V_{CANL} = 0\text{ V}$ |
| Voltage detection threshold for short-circuit to battery voltage on CANH and CANL | $V_{det(th)}$ | 6.5 | 7.3 | 8.0 | V | |
| CANH wake-up voltage threshold | $V_{H,wk}$ | 1.2 | 1.9 | 2.7 | V | low power modes |
| CANL wake-up voltage threshold | $V_{L,wk}$ | 2.2 | 3.1 | 3.9 | V | low power modes |
| CANH single-ended receiver threshold | V_{CANH} | 1.6 | 2.1 | 2.6 | V | failure cases 3, 5 and 7 |
| CANL single-ended receiver threshold | V_{CANL} | 2.4 | 2.9 | 3.4 | V | failure case 6 and 6a |
| CANL leakage current | I_{CANLI} | -5 | | 5 | μA | $V_{CC} = 0\text{ V}$, $V_S = 0\text{ V}$, $V_{CANL} = 13.5\text{ V}$, $T_j < 85\text{ °C}$ |
| CANH leakage current | I_{CANHI} | -5 | | 5 | μA | $V_{CC} = 0\text{ V}$, $V_S = 0\text{ V}$, $V_{CANH} = 5\text{ V}$, $T_j < 85\text{ °C}$ |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ °C} < T_j < 150\text{ °C}$ (max. 125 °C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|-----------|--------|--------------|------|------|------|----------------|
| | | min. | typ. | max. | | |

Termination Outputs RTL, RTH

| | | | | | | |
|--------------------------------------|-------------|------|-----|-----|---------------|---|
| RTL to V_{CC} switch-on resistance | R_{RTL} | | 40 | 95 | Ω | $I_o = -10\text{ mA}$; |
| RTL to BAT switch series resistance | R_{oRTL} | 5 | 15 | 30 | $k\Omega$ | V_{BAT} -stand-by or sleep mode |
| RTH to ground switch-on resistance | R_{RTH} | | 40 | 95 | Ω | $I_o = 10\text{ mA}$; |
| RTH output voltage | V_{oRTH} | | 0.7 | 1.0 | V | $I_o = 1\text{ mA}$; sleep mode or V_{BAT} -stand-by |
| RTH pull-down current | I_{RTHpd} | 40 | 75 | 120 | μA | failure cases 6 and 6a |
| RTL pull-up current | I_{RTLpu} | -120 | -75 | -40 | μA | failure cases 3, 3a, 5 and 7 |
| RTH leakage current | I_{RTHl} | -5 | | 5 | μA | $V_{CC} = 0\text{ V}$, $V_S = 0\text{ V}$, $V_{RTH} = 5\text{ V}$, $T_j < 85\text{ °C}$ |
| RTL leakage current | I_{RTLl} | -5 | | 5 | μA | $V_{CC} = 0\text{ V}$, $V_S = 0\text{ V}$, $V_{RTL} = 12\text{ V}$, $T_j < 85\text{ °C}$ |

CAN-Transceiver

Dynamic Characteristics

| | | | | | | |
|--|---------------|-----|-----|-----|---------------|--|
| CANH and CANL bus output transition time recessive-to-dominant | t_{rd} | 0.6 | 1.2 | 2.1 | μs | 10% to 90%; $C_1 = 10\text{ nF}$; $C_2 = 0$; $R_1 = 100\text{ }\Omega$ |
| CANH and CANL bus output transition time dominant-to-recessive | t_{dr} | 0.3 | 0.6 | 1.3 | μs | 10% to 90%; $C_1 = 1\text{ nF}$; $C_2 = 0$; $R_1 = 100\text{ }\Omega$ |
| Minimum dominant time for wake-up on CANL or CANH | $t_{wu(min)}$ | 12 | 20 | 32 | μs | Stand-by modes |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ }^{\circ}\text{C} < T_J < 150\text{ }^{\circ}\text{C}$ (max. 125°C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|---|--------------------|--------------|------|------|---------------|---|
| | | min. | typ. | max. | | |
| Failure cases 3 and 6 detection time | t_{fail} | 30 | 45 | 80 | μs | |
| Failure case 6a detection time | | 2.0 | 4.8 | 8.0 | ms | |
| Failure cases 5, 6, 6a and 7 recovery time | | 30 | 45 | 80 | μs | |
| Failure cases 3 recovery time | | 250 | 500 | 750 | μs | |
| Failure cases 5 and 7 detection time | | 1.0 | 2.0 | 4.0 | ms | |
| Failure cases 5 detection time | t_{fail} | 0.4 | 1.0 | 2.4 | ms | Stand-by modes |
| Failure cases 6, 6a and 7 detection time | | 0.8 | 4.0 | 8.0 | ms | Stand-by modes |
| Failure cases 5, 6, 6a and 7 recovery time | | 0.4 | 1.0 | 2.4 | μs | Stand-by modes |
| Propagation delay TxD-to-RxD LOW (recessive to dominant) | $t_{\text{PD(L)}}$ | – | 1.5 | 2.1 | μs | $C_1 = 100\text{ pF}$; $C_2 = 0$; $R_1 = 100\text{ }\Omega$; no failures and bus failure cases 1, 2, 3a and 4 |
| | | – | 1.7 | 2.4 | μs | $C_1 = C_2 = 3.3\text{ nF}$; $R_1 = 100\text{ }\Omega$; no bus failure and failure cases 1, 2, 3a and 4 |
| | | – | 1.8 | 2.5 | μs | $C_1 = 100\text{ pF}$; $C_2 = 0$; $R_1 = 100\text{ }\Omega$; bus failure cases 3, 5, 6, 6a and 7 |
| | | – | 2.0 | 2.6 | μs | $C_1 = C_2 = 3.3\text{ nF}$; $R_1 = 100\text{ }\Omega$; bus failure cases 3, 5, 6, 6a and 7 |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ °C} < T_j < 150\text{ °C}$ (max. 125 °C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|--|-------------|--------------|------|------|---------------|---|
| | | min. | typ. | max. | | |
| Propagation delay TxD-to-RxD HIGH (dominant to recessive) | $t_{PD(H)}$ | – | 1.5 | 2.0 | μs | $C_1 = 100\text{ pF}$; $C_2 = 0$; $R_1 = 100\text{ }\Omega$; no failures and bus failure cases 1, 2, 3a and 4 |
| | | – | 2.5 | 3.5 | μs | $C_1 = C_2 = 3.3\text{ nF}$; $R_1 = 100\text{ }\Omega$; no bus failure and failure cases 1, 2, 3a and 4 |
| | | – | 1.0 | 2.1 | μs | $C_1 = 100\text{ pF}$; $C_2 = 0$; $R_1 = 100\text{ }\Omega$; bus failure cases 3, 5, 6, 6a and 7 |
| | | – | 1.5 | 2.6 | μs | $C_1 = C_2 = 3.3\text{ nF}$; $R_1 = 100\text{ }\Omega$; bus failure cases 3, 5, 6, 6a and 7 |
| Edge-count difference (falling edge) between CANH and CANL for failure cases 1, 2, 3a and 4 detection | n_e | – | 4 | – | – | |
| Edge-count difference (rising edge) between CANH and CANL for failure cases 1, 2, 3a and 4 recovery | | – | 2 | – | – | |
| TxD permanent dominant disable time | t_{TxD} | 1.3 | 2.0 | 3.5 | ms | |

SPI-Interface

Logic Inputs DI, CLK and CSN

| | | | | | | |
|-----------------------------|------------|---------------------|------|---------------------|---------------|-------------------------------|
| H-input voltage threshold | V_{IH} | – | – | $0.7 \times V_{CC}$ | V | – |
| L-input voltage threshold | V_{IL} | $0.3 \times V_{CC}$ | – | – | V | – |
| Hysteresis of input voltage | V_{IHV} | 50 | 200 | 500 | mV | – |
| Pull up current at pin CSN | I_{ICSN} | – 100 | – 25 | – 5 | μA | $V_{CSN} = 0.7 \times V_{CC}$ |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ }^{\circ}\text{C} < T_J < 150\text{ }^{\circ}\text{C}$ (max. $125\text{ }^{\circ}\text{C}$ for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|---|----------------------|--------------|------|------|---------------|--|
| | | min. | typ. | max. | | |
| Pull down current at pin DI and CLK | $I_{\text{ICLK/DI}}$ | 5 | 25 | 100 | μA | $V_{\text{DI}} = 0.2 \times V_{\text{CC}}$ |
| Input capacitance at pin CSN, DI or CLK | C_{I} | – | 10 | 15 | pF | $0\text{ V} < V_{\text{CC}} < 5.25\text{ V}$ |

Logic Output DO

| | | | | | | |
|-----------------------------|-------------------|-----------------------|-----------------------|-----|---------------|--|
| H-output voltage level | V_{DOH} | $V_{\text{CC}} - 1.0$ | $V_{\text{CC}} - 0.7$ | – | V | $I_{\text{DOH}} = 1\text{ mA}$ |
| L-output voltage level | V_{DOL} | – | 0.2 | 0.4 | V | $I_{\text{DOL}} = -1.6\text{ mA}$ |
| Tri-state leakage current | I_{DOLK} | – 10 | – | 10 | μA | $V_{\text{CSN}} = V_{\text{CC}}$ $0\text{ V} < V_{\text{DO}} < V_{\text{CC}}$ |
| Tri-state input capacitance | C_{DO} | – | 10 | 15 | pF | $V_{\text{CSN}} = V_{\text{CC}}$ $0\text{ V} < V_{\text{CC}} < 5.25\text{ V}$ |

Data Input Timing

| | | | | | | |
|---|-------------------|------|---|-----|----|---|
| Clock period | t_{pCLK} | 1000 | – | – | ns | – |
| Clock high time | t_{CLKH} | 500 | – | – | ns | – |
| Clock low time | t_{CLKL} | 500 | – | – | ns | – |
| Clock low before CSN low | t_{bef} | 500 | – | – | ns | – |
| CSN setup time | t_{lead} | 500 | – | – | ns | – |
| CLK setup time | t_{lag} | 500 | – | – | ns | – |
| Clock low after CSN high | t_{beh} | 500 | – | – | ns | – |
| DI setup time | t_{DISU} | 250 | – | – | ns | – |
| DI hold time | t_{DIHO} | 250 | – | – | ns | – |
| Input signal rise time at pin DI, CLK and CSN | t_{rIN} | – | – | 200 | ns | – |
| Input signal fall time at pin DI, CLK and CSN | t_{fIN} | – | – | 200 | ns | – |

2.3 Electrical Characteristics (cont'd)

$V_S = 13.5\text{ V}$; $I_{CC} = 1\text{ mA}$; normal mode; all outputs open; $-40\text{ }^{\circ}\text{C} < T_j < 150\text{ }^{\circ}\text{C}$ (max. 125°C for CAN circuit characteristics); all voltages with respect to ground; positive current defined flowing into pin; unless otherwise specified.

| Parameter | Symbol | Limit Values | | | Unit | Test Condition |
|--------------------|-------------|--------------|------|------|------|---|
| | | min. | typ. | max. | | |
| Data Output Timing | | | | | | |
| DO rise time | t_{rDO} | — | 50 | 100 | ns | $C_L = 100\text{ pF}$ |
| DO fall time | t_{fDO} | — | 50 | 100 | ns | $C_L = 100\text{ pF}$ |
| DO enable time | t_{ENDO} | — | — | 250 | ns | low impedance |
| DO disable time | t_{DISDO} | — | — | 250 | ns | high impedance |
| DO valid time | t_{VADO} | — | 100 | 250 | ns | $V_{DO} < 0.1\ V_{CC}$; $V_{DO} > 0.9\ V_{CC}$; $C_L = 100\text{ pF}$ |

Thermal Prewarning and Shutdown (junction temperatures) *guaranteed by design*

| | | | | | | |
|---|---------------------|-----|------|-----|--------------------|--|
| OUTHS thermal prewarning ON temperature | T_{jPW} | 120 | 145 | 170 | $^{\circ}\text{C}$ | bit 0 of SPI diagnosis word |
| OUTHS thermal prewarning hyst. | ΔT | – | 30 | – | K | – |
| OUTHS thermal shutdown temp. | T_{jSD} | 150 | 175 | 200 | $^{\circ}\text{C}$ | – |
| OUTHS thermal switch-on temp. | T_{jSO} | 120 | – | 170 | $^{\circ}\text{C}$ | – |
| OUTHS thermal shutdown hyst. | ΔT | – | 30 | – | K | – |
| OUTHS ratio of SD to PW temp. | T_{jSD} / T_{jPW} | | 1.20 | – | – | – |
| Vcc thermal shutdown temp. | T_{jSD} | 155 | 185 | 200 | $^{\circ}\text{C}$ | hysteresis 15°K (typ.) |
| OUTHS thermal shutdown temp. | T_{jSD} | | 150 | | $^{\circ}\text{C}$ | hysteresis 15°K (typ.) |

3 Timing Diagrams

Figure 4: SPI-Data Transfer Timing

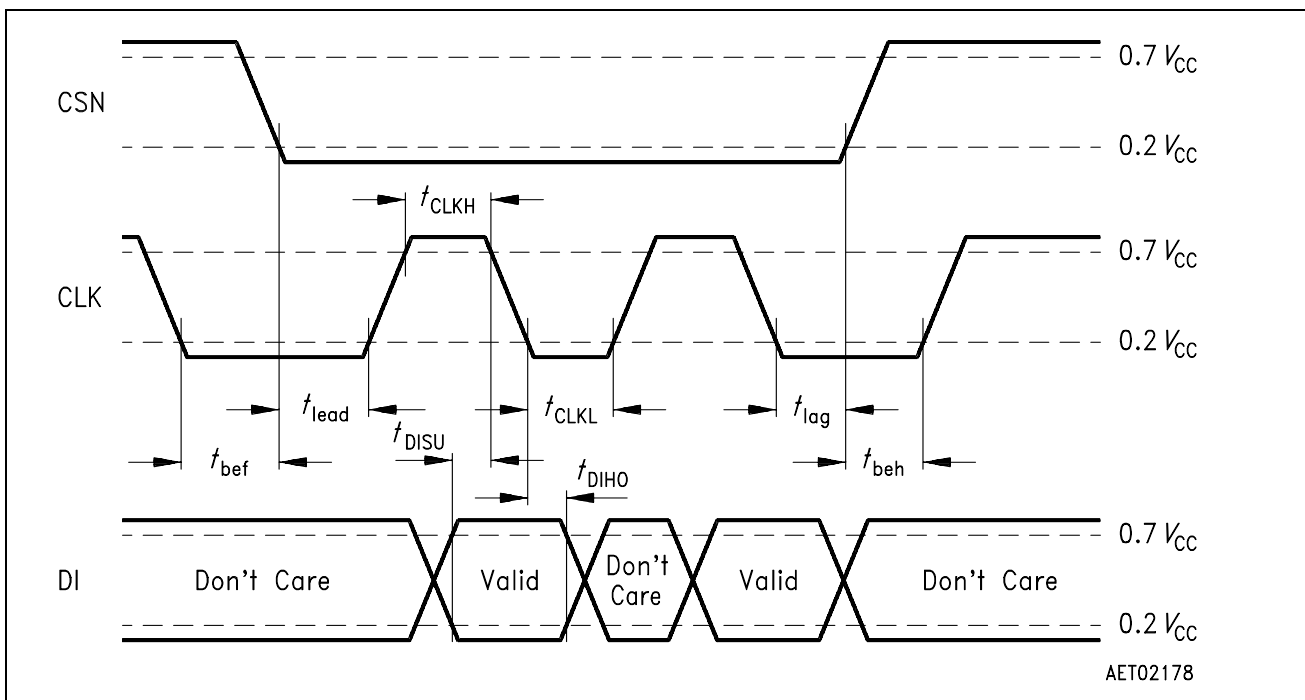
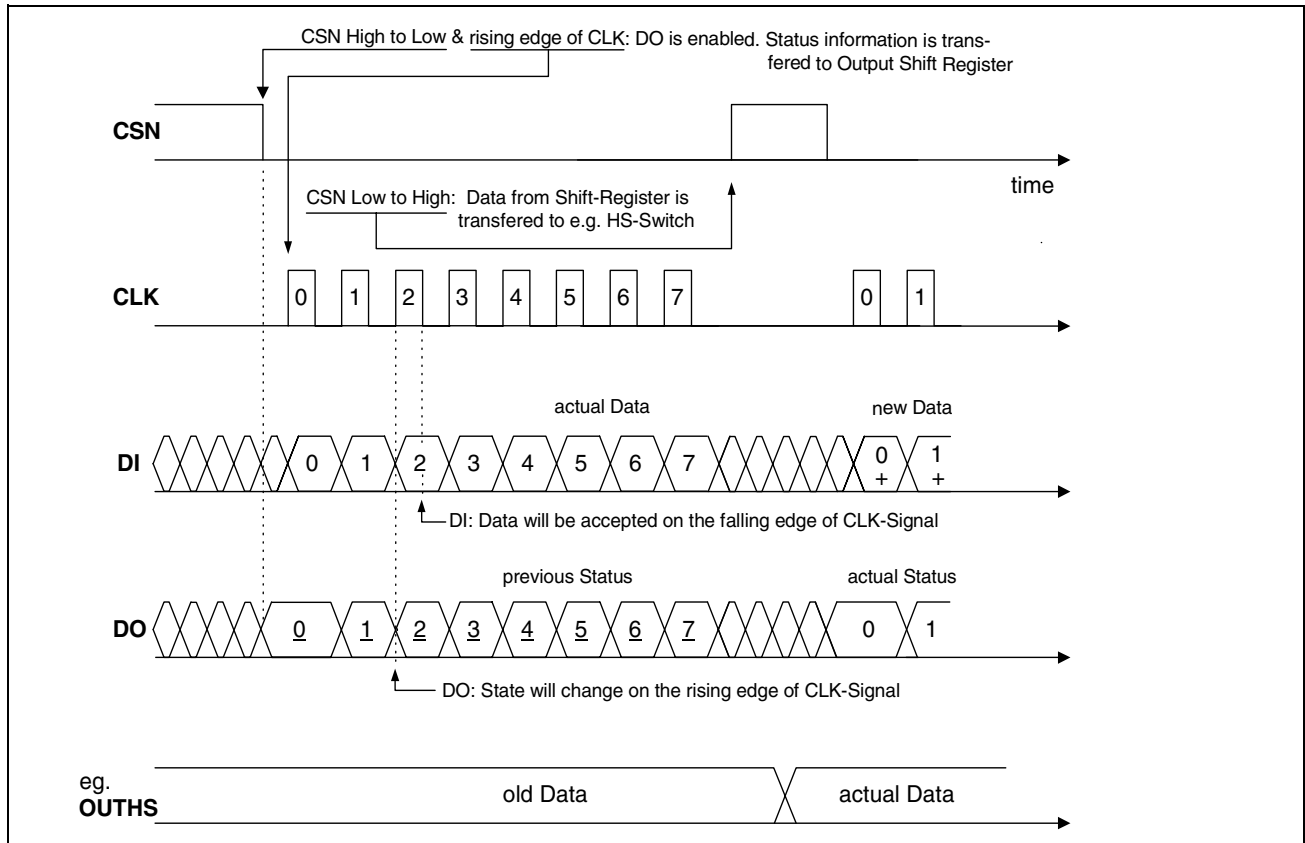


Figure 5: SPI-Input Timing

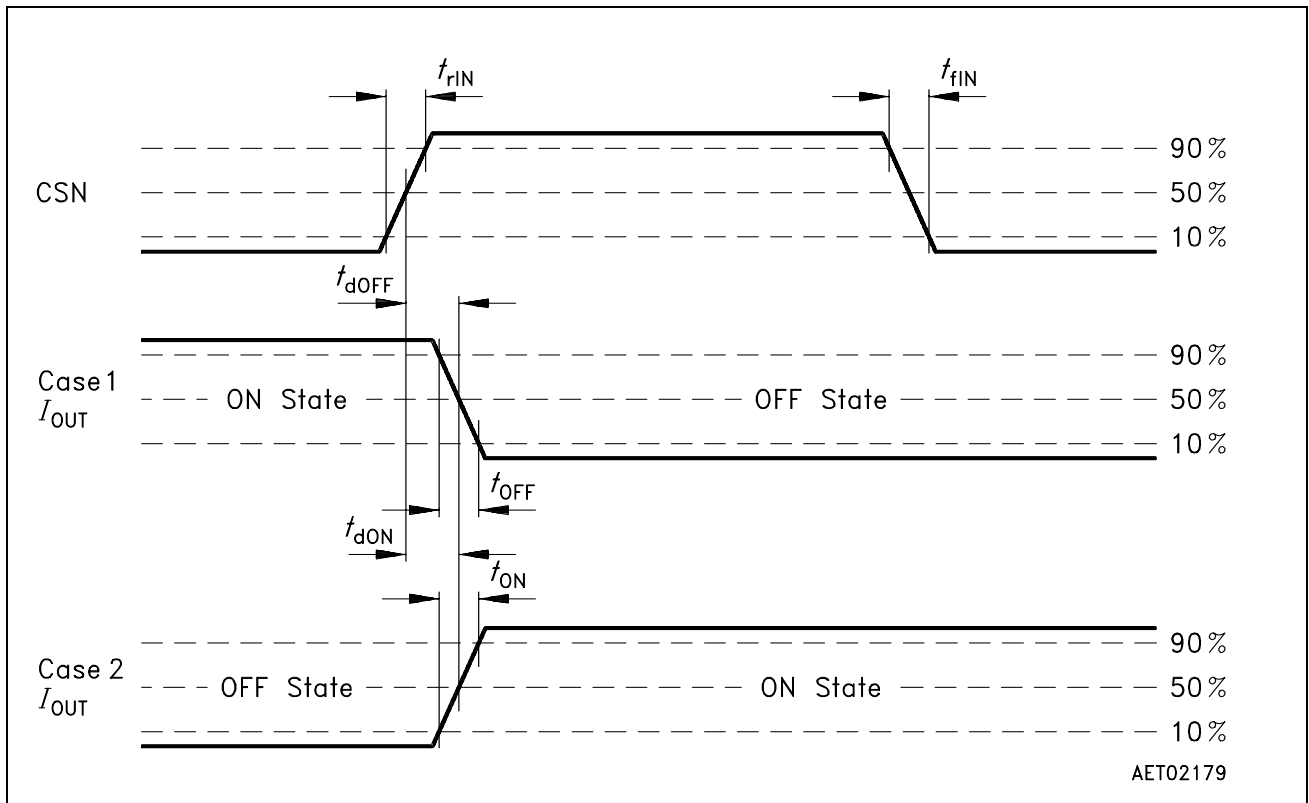


Figure 6: Turn OFF/ON Time

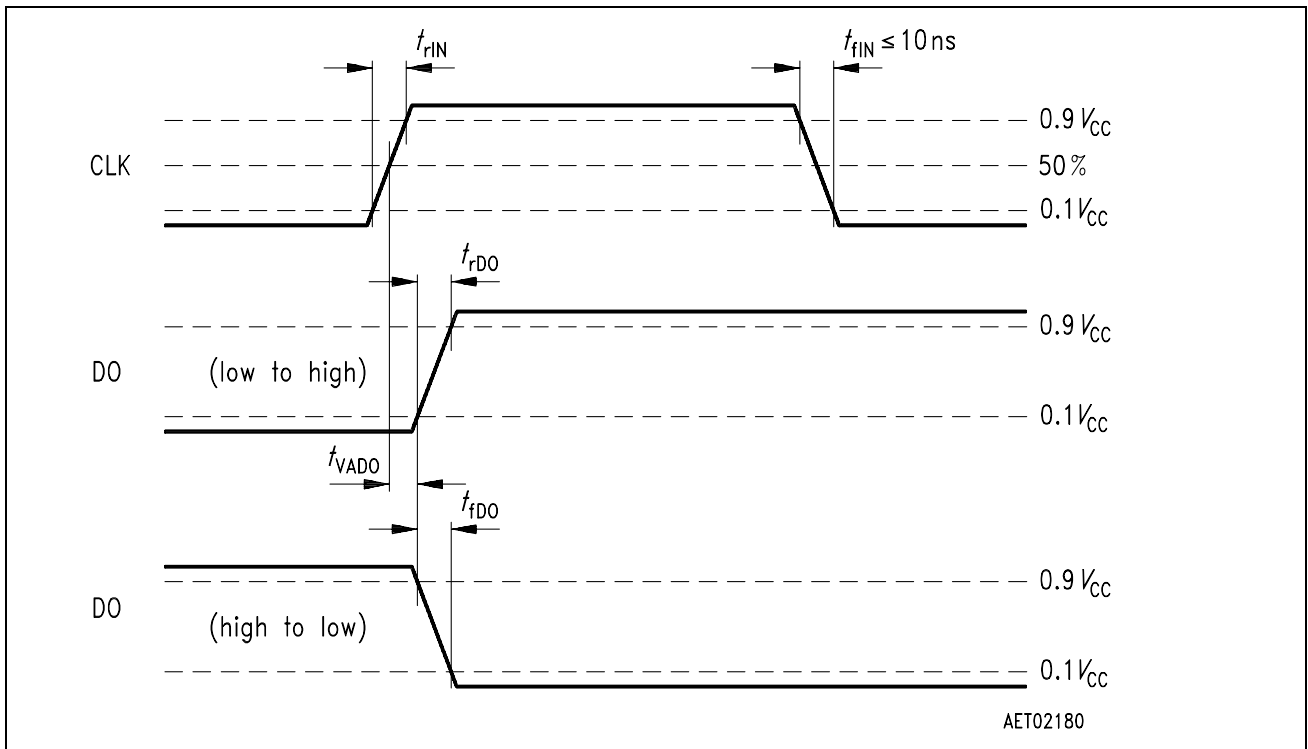


Figure 7: DO Valid Data Delay Time and Valid Time

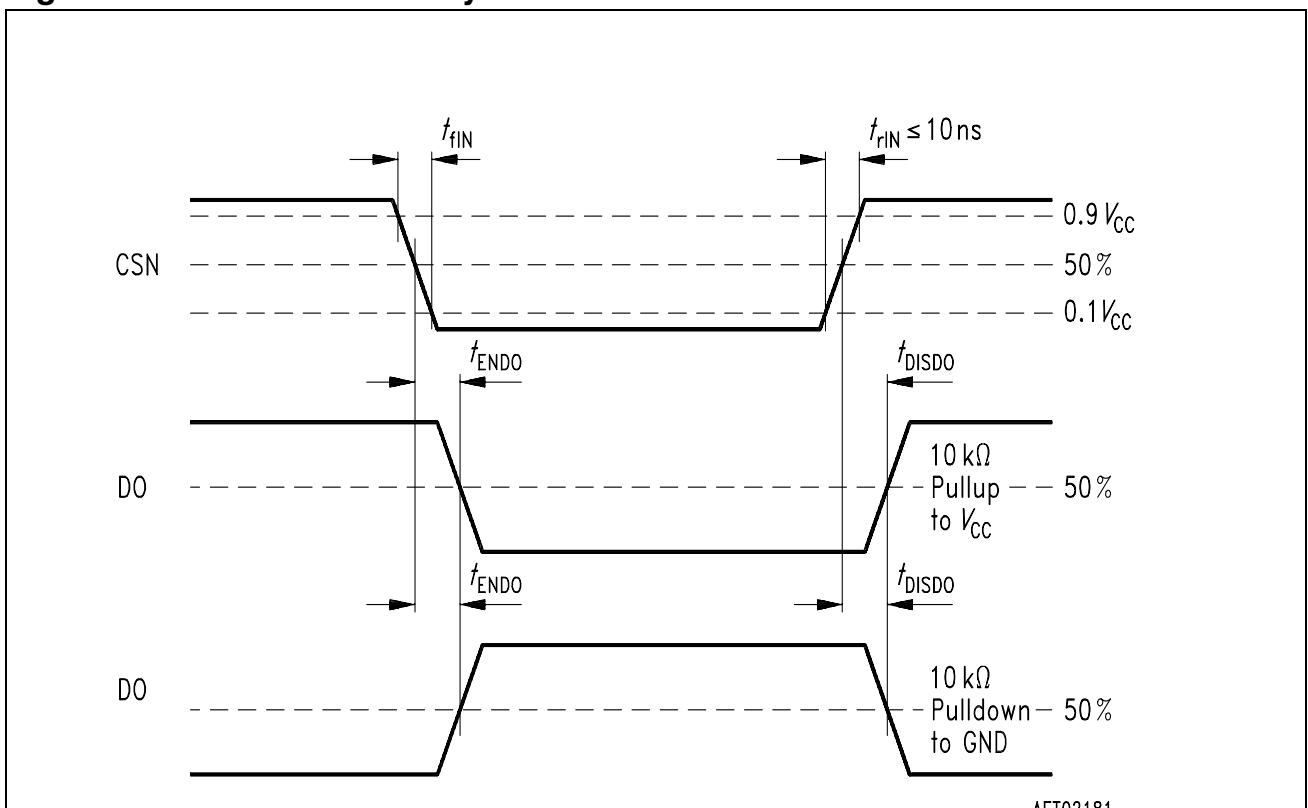


Figure 8: DO Enable and Disable Time

Figure 9: Watchdog Time-Out Definitions

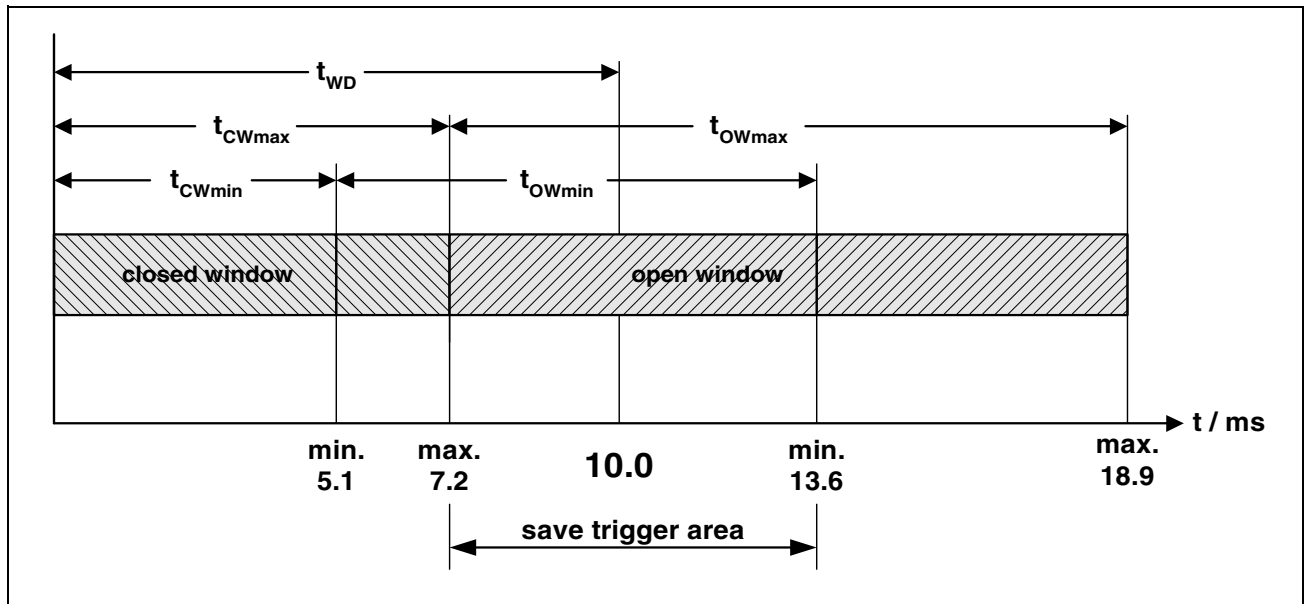


Figure 10: Watchdog Timing Diagram

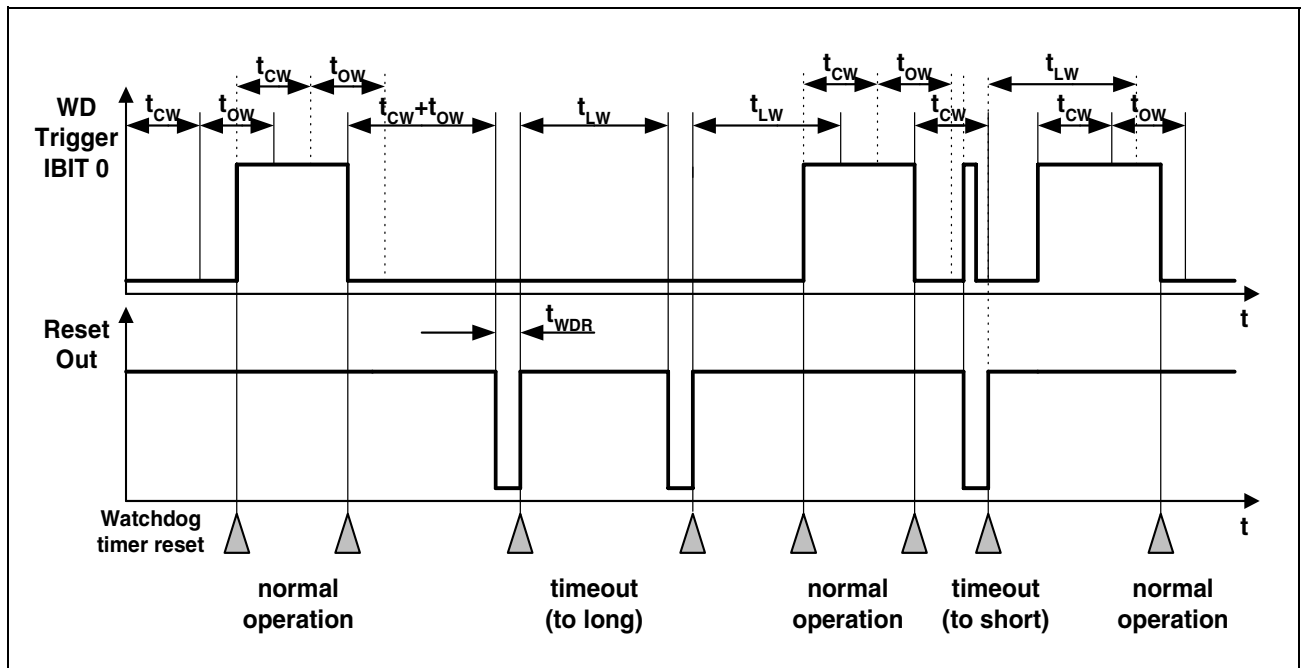


Figure 11: Reset Timing Diagram

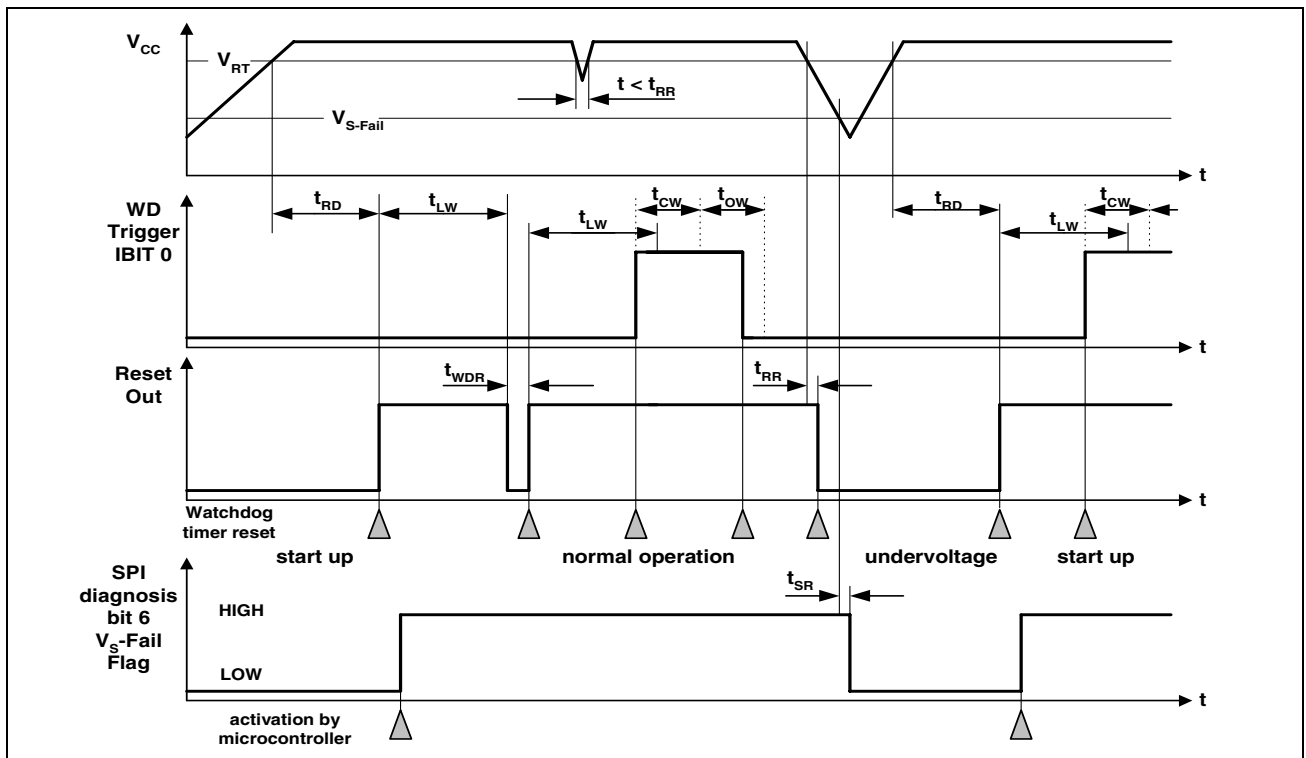
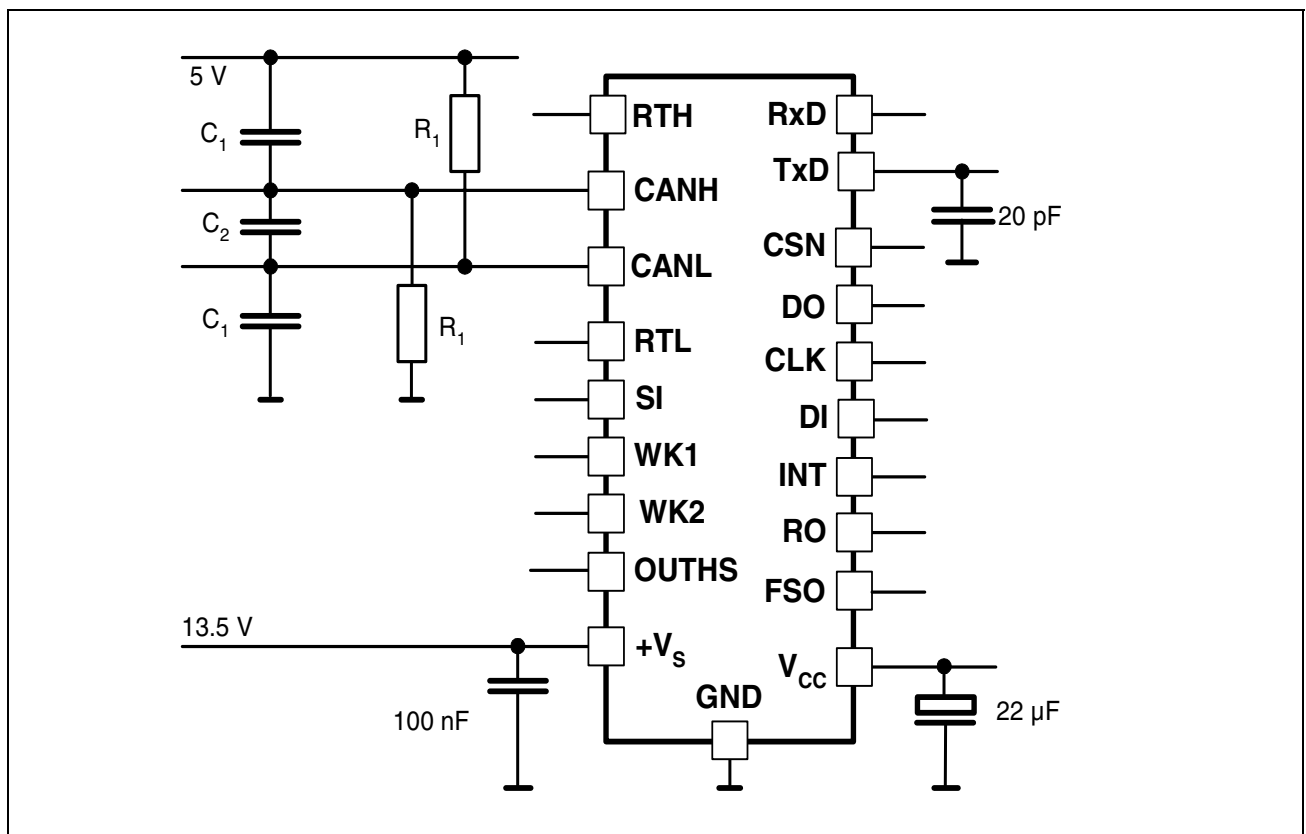


Figure 12: Test Circuit



4 Application

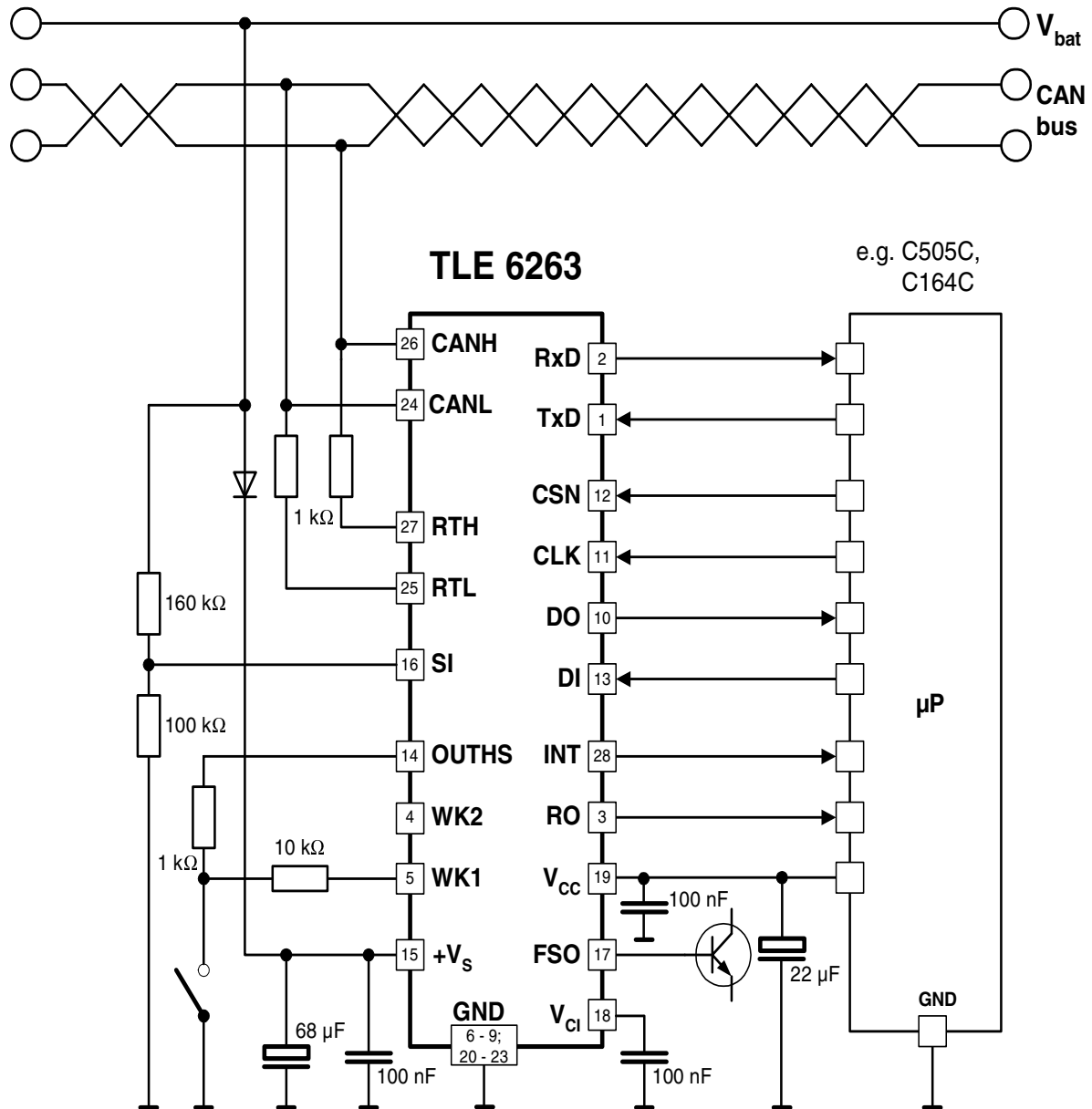
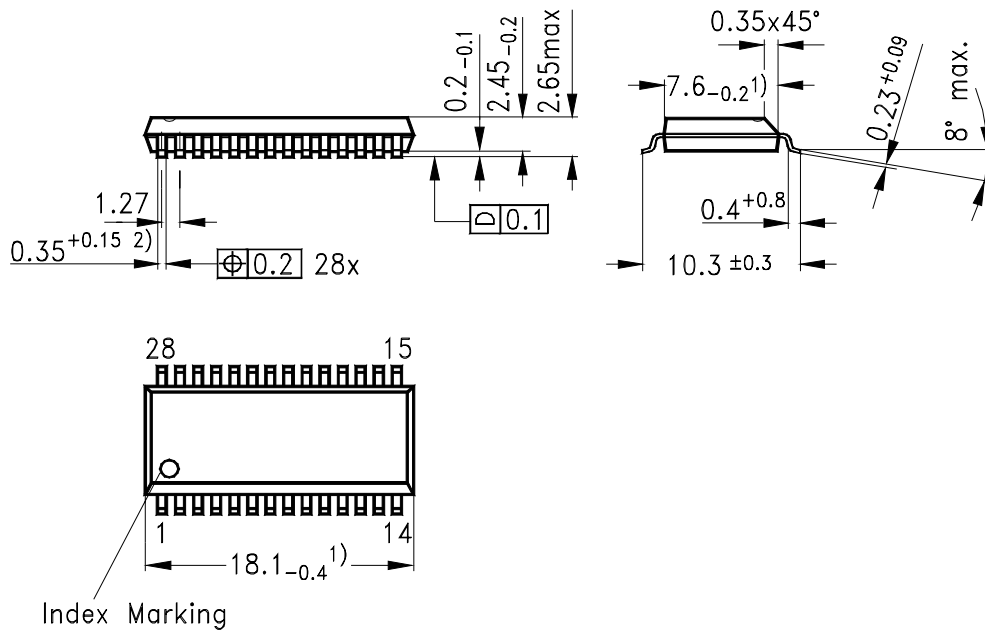


Figure 13
Application Circuit

5 Package Outlines

P-DSO-28-6

(Plastic Dual Small Outline Package)



- 1) Does not include plastic or metal protrusion of 0.15 max. per side
- 2) Does not include dambar protrusion of 0.05 max. per side

GPS05123

Sorts of Packing

Package outlines for tubes, trays etc. are contained in our Data Book "Package Information".

SMD = Surface Mounted Device

Dimensions in mm

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